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						First Named Inventor:	Soojin Oh		
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						Examiner:	Phasge, Arun S.		
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10/615,842 U.S. Department of Commerce Application No.: Patent and Trademark Office July 10, 2003 Filing Date: First Named Inventor: Soojin Oh List of Documents Cited by Applicant Group: 1753 Examiner: Phasge, Arun S. Attorney Docket No.: 421/170/8/2 CIP **U.S. PATENT DOCUMENTS** Name of Patentee or Applicant of Cited Examiner Cite **Document Number Publication Date** Pages, Columns, Lines, Initial No. Document where relevant passages or relevant figures appear 1. 2003/0102222 06/05/2003 Zhou et al. **FOREIGN PATENT DOCUMENTS** Examiner Cite **Document Number Publication Date** Name of Patentee or Applicant Pages, columns, lines T Initials No. where relevant (country code, no., kind passages appear code (if known) OTHER DOCUMENTS Cite Include Author (in CAPITAL LETTERS), Title, Journal, Date, Pertinent Pages, Etc. Т Examiner Initials No. International Search Report for PCT/US04/20150 dated March 10, 2006. EXAMINER DATE CONSIDERED \_

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